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Sheet 1 of 1

FORM PTO-1449	U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE	ATTORNEY DOCKET NO. 392.1680	APPLICATION NO. 09/546,214
LIST OF REFERENCES CITED BY APPLICANT <i>(Use several sheets if necessary)</i>		FIRST NAMED INVENTOR Atsushi WATANABE et al.	
		FILING DATE April 10, 2000	GROUP ART UNIT 2721

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NO.	DATE	NAME	CLASS	SUB-CLASS	FILING DATE
<i>SP</i>	AA	5,845,048	12/01/98	Masumoto			

FOREIGN PATENT DOCUMENTS

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION YES NO
<i>SP</i>	AB	2 085 629	04/28/82	United Kingdom			

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)			TRANSLATION YES NO
<i>SP</i>	AC	Ichiro Masaki, "Industrial Vision Systems Based on Application-Specific IC Chips", IEICE Transactions, Institute of Electronics, Vol. E74 No. 6, June 1, 1991, pages 1728-1734	
<i>SP</i>	AD	Michael Magee et al, "An Industrial Model Based Computer Vision System", Journal of Manufacturing Systems, Society of Manufacturing Engineers, Vol. 14 No. 3, 1995, pages 169-186	
<i>SP</i>	AE	Sarah Wang et al, "Model-Based Vision for Robotic Manipulation of Twisted Tubular Parts: Using Affine Transforms and Heuristic Search", Robotics and Automation, IEEE, May 8, 1994, pages 208-215	
<i>SP</i>	AF	Kohtaro Ohba et al, "Recognition of the Multi Specularity Objects for Bin-picking Task", IEEE, November 4, 1996, pages 1440-1447	
<i>SP</i>	AG	Toshiyuki Amano et al, "Eignespace Approach for Object Recognition and Its Pose Detection", Systems and Computer in Japan, Vol. 31 No. 11, October 2000, pages 60-69	
<i>SP</i>	AH	J. Hornegger et al, "Statistical Learning, Localization, and Identification of Objects", IEEE, June 20, 1995, pages 914-919	
<i>SP</i>	AI	Juan Andrade-Cetto et al., Object Recognition, "Wiley Encyclopedia of Electrical Engineering", April 1, 2000, pages 449-470	

EXAMINER <i>George R. S.</i>	DATE CONSIDERED <i>4-22-04</i>
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	